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MAA			n, "Computational A	lchemy: T	he Search for	New Superha	ard
1411/		<del></del>	l, pgs. 22-27 (1998)	1 1	C:C WW	N. 1. 1. 1. 1. 1. 1. 1. 1. 1. 1. 1. 1. 1.	TT 3.75
MILL			Applied Physics, "La	-	-		11-V1
1001			or Device Technologi				wth.
MILL			ysics Letters, "Initial Plasma-assisted, Gas				
their .	l i	pgs. 37-39 (199		-source ivid	neculai Beam	Epitaxy , v	01.
1222			e American Ceramic S	Society. "C	omposition ar	nd Properties	of
MA			id Solutions", Vol. 65				
2777						ion of Phase	
JNH		Rafaniello, et al., Journal of the American Ceramic Society, "Investigation of Phase Stability in the System SiC-AIN", Vol. 66, No. 4, pgs. 272-276 (1983)					
r.t.N.	Zangvil, e	t al., Journal of	the American Ceram	ic Society,	"Phase Relati		e
WH		Silicon Carbide-Aluminum Nitride System", Vol. 71, No. 10, pgs. 884-890 (1988)					
M	1 1		Technology and Phys			Epitaxy", Cha	ipter
1114	2 ngc 15.	46 and Chapter	11 nos 345-386 Pla	enum Press	(1985)		

E JOJON	
7 5005 A	
	Kern, et al., Journal of Materials Research, "Solid Solutions of AIN and SiC Grown by Plasma-assisted, Gas-source Molecular Beam Epitaxy, Vol. 8, No. 7, pgs. 1477-1480 (1993)
MA	Kern, et al., Journal of Materials Research, "Aluminum Nitride-silicon Carbide Solid Solutions Grown by Plasma-assisted, Gas-source Molecular Beam Epitaxy, Vol. 13, No. 7, pgs. 1816-1822 (1998)
WA	Jenkins, et al., Journal of Crystal Growth, "Growth of Solid Solutions of Aluminum Nitride and Silicon Carbide by Metalorganic Chemical Vapor Deposition", Vol. 128, Nos. 1-4, pgs. 375-378 (1993)
MA	Safaraliev, et al., Soviet Physics Semiconductors, "Wide-gap (SiC) <sub>1-x</sub> (AIN) <sub>x</sub> Solid Solutions", Vol. 25, No. 8, pgs. 865-871 (1991)
	MacDiarmid, Journal of Inorganic and Nuclear Chemistry, "Pseudo-halogen Derivatives of Monosilane", Vol. 2, No. 2, pgs. 88-94 (1956)
MA	Goldfarb, The Journal of Chemical Physics, "Infrared Spectrum and Structure of Germyl Cyanide", Vol. 37, No. 3, pgs. 642-646 (1962)
MA	Pandey, et al. Journal of Applied Physics, "A Theoretical Study of Stability, Electronic and Optical Properties of GeC and SnC", Vol. 88, No. 11, p. 6462-6466 (2000)

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**EXAMINER** 

